Notice of References Cited Application/Control No. 10/602,672 Examiner James A. Dudek Applicant(s)/Patent Under Reexamination KIM ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2004/0057006	03-2004	Park et al.	349/153
	В	US-2003/0179337	09-2003	Park et al.	349/153
	С	US-2003/0169392	09-2003	Park et al.	349/153
	D	US-2003/0038914	02-2003	Kim et al.	349/153
	Ę	US-2001/0012088	08-2001	Jeong, Jae-Gyu	349/153
	F	US-6,741,316	05-2004	Park et al.	349/153
	G	US-6,628,365	09-2003	Park et al.	349/153
	Н	US-6,573,972	06-2003	Sasaki, Takeshi	349/190
	1	US-6,573,968	06-2003	Jeong, Jae-Gyu	349/153
	J	US-6,542,215	04-2003	Lee et al.	349/153
	К	US-6,137,559	10-2000	Tanaka et al.	349/153
	L	US-6,099,672	08-2000	Yamazaki et al.	156/109
	М	US-6,066,018	05-2000	Grupp et al.	445/25

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0	-				
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	8	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.